INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(Use as many sheets as necessary)

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	Complete if Known	VILE ?
Application Number	10/721,903	13.
Filing Date	November 26, 2003	10.000
First Named Inventor	Nobuhiro Komine	Ma
Art Unit	2851	3.
Examiner Name	D. Rutledge	Tr Locality
Attorney Docket Number	3180.0342	THOM

	U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS						
Examiner Cite Initials No.	Cite	Document Number	Issue or	Name of Patentee or	Pages, Columns, Lines, Where		
	No.'	Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY	Applicant of Cited Document .	Relevant Passages or Relevant Figures Appear		
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FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No. ¹	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁶ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation ⁶
D.R.		JP 2001-319871	11/16/01	Nikon Corp.		Abstract
DR	-	JP 2000-310850	11/7/00	Toshiba Corp.		Abstract
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	NON PATENT LITERATURE DOCUMENTS				
Examiner Initials	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation ⁶		
D.E.		Notice of Grounds for Rejection, issued by the Japanese Patent Office, mailed June 21, 2005, in Japanese Patent Application Serial No. P2002-342798, and English-language translation thereof			
72		DIRKSEN et al., "Focus and exposure dose determination using stepper alignment," SPIE (1996), 2726:799-808			
D.R.		STARIKOV, "Exposure Monitor Structure," SPIE (1990), 1261:315-324			

Examiner Signature	But	ical	Date Considered	11/5	105	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.